

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/625,902	OTAKE, HIDEYUKI	
Examiner		Art Unit		Page 1 of 1
Jean B. Jeanglaude		2819		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,918,448	04-1990	Hauviller et al.	341/145
	B	US-4,973,979	11-1990	Ikeda, Hiroshi	341/154
	C	US-5,604,501	02-1997	McPartland, Richard J.	341/144
	D	US-5,111,205	05-1992	Morlon, Patrice P.	341/156
	E	US-5,523,721	06-1996	Segawa et al.	330/86
	F	US-5,703,588	12-1997	Rivoir et al.	341/159
	G	US-5,731,775	03-1998	Gross et al.	341/155
	H	US-5,841,382	11-1998	Walden et al.	341/120
	I	US-5,969,657	10-1999	Dempsey et al.	341/145
	J	US-5,999,115	12-1999	Connell et al.	341/145
	K	US-6,157,335	12-2000	Suzuki et al.	341/154
	L	US-6,400,300	06-2002	Leung et al.	341/154
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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